

Search Notes

Application/Control No.

09/054,864

Examiner

Hai Tran

Applicant(s)/Patent under
Reexamination

FRINK ET AL.

Art Unit

2611

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
NPL search for IEEE-1394	3/15/2006	HVT